

UK Advanced Instrumentation Training

Circuit Design 3 & 4 Simulation LTspice 1 & 2

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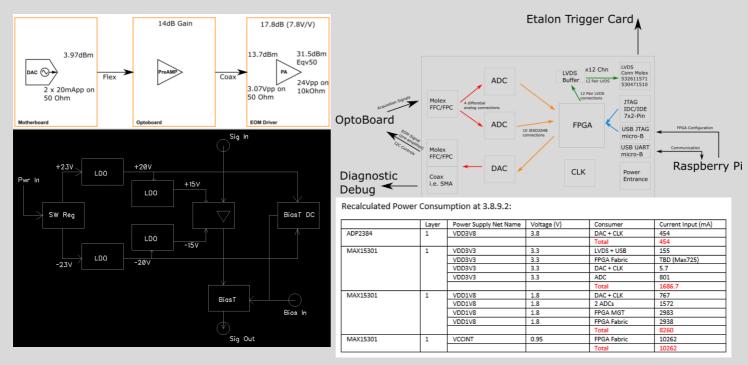




- WorkflowSimulation
 - Analyze -> Block Diagram, Specs
 - Schematic -> Circuit topology, Constraints
 - Layout -> GERBER, BOM, Assembly-files
 - Manufacturing (fabrication, population, assembly)
 - Debug, Characterization -> Reports
 - (Revision)



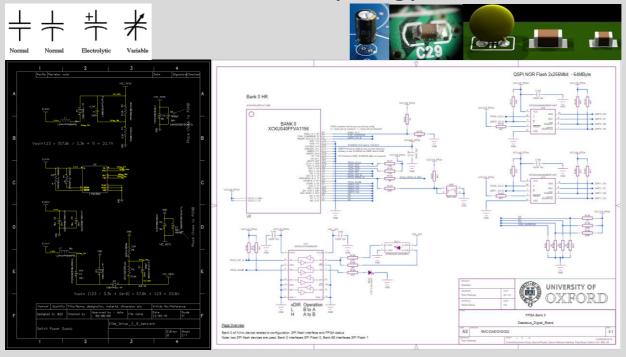
- Workflow
 - Analyze -> Block Diagram, Specs





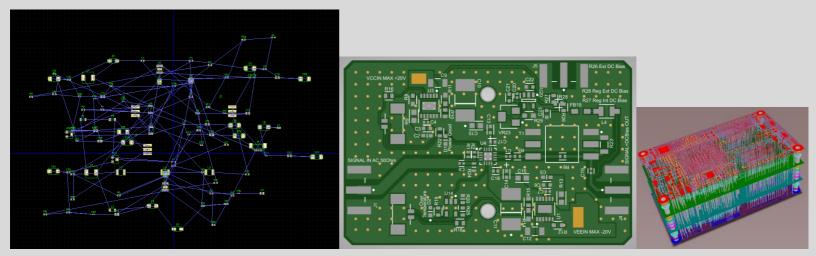
Workflow

Schematic -> Circuit topology, Constraints





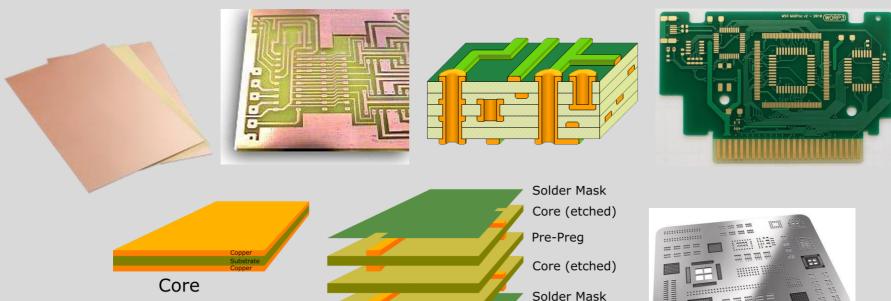
- Workflow
 - Layout -> GERBER, BOM, Assembly-files

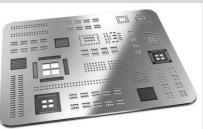


Source: https://www.wellpcb.com/



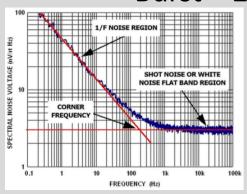
- Workflow
 - Manufacturing (fabrication, population, assembly)

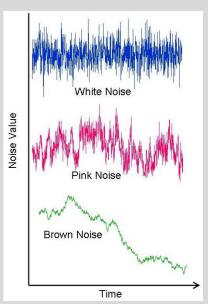






- Noise
 - Thermal \sim quasi-white, Gaussian, 4kTR; Conductor
 - Shot \sim white, Gaussian, 2e|I|; Semiconductor
 - 1/f, flicker ~ f-depend; Anything
 - Burst ~ 2-value, *f*-depend; Semiconductor

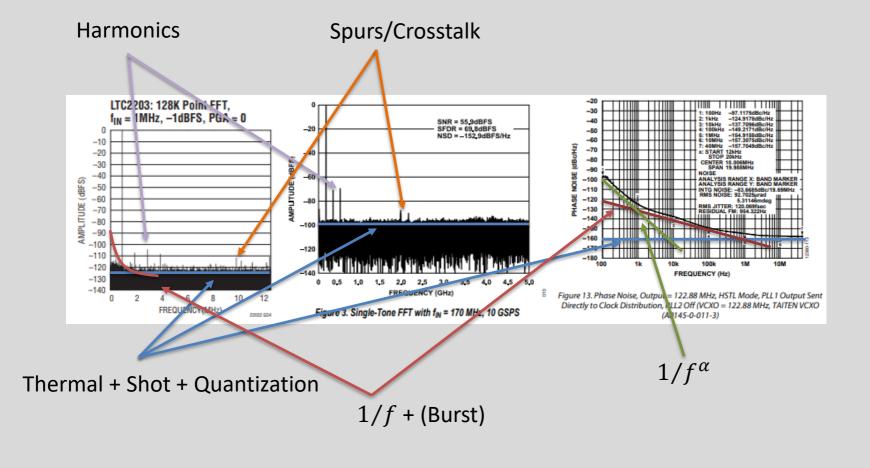






- Interference/Crosstalk
 - Data/Clock dependent ~ non-stationary, f-depend
- Systematic
 - Harmonics, Spurs ~ f-depend; Amp-linearity, ADC, DAC
 - Quantization Noise ~ quasi-white, uniform; ADC
 - Aliasing/Mirror Noise~ Signal x Sinc, uniform; ADC, DAC
 - Clock Phase Noise ~ $1/f^{\alpha}$; resonant, quartz, PLL







- Noise
 - Units PSD vs PSD

$$\bar{P} = \lim_{T \to \infty} \frac{1}{T} \int_{-T/2}^{T/2} \frac{x^2(t)}{R} dt$$

x is the random variable of noise, with the unit of voltage Resistivity R is sometimes ignored to 1, \overline{P} is average power

$$\bar{P} = \int_0^B S_x(f) \mathrm{d}f$$

B is the bandwidth, S_x is the power spectrum density, with the unit of Power per Bandwidth, i.e. dBm/Hz

$$x_{\rm RMS} = \sqrt{\bar{P}R}$$

 $x_{\rm RMS}$ is the root-mean-square of the noise, with the unit of voltage

$$v_n(f) = \sqrt{\overline{S_x(f)}R} = \sqrt{\frac{\bar{x}^2}{RB}}$$
 This is only in

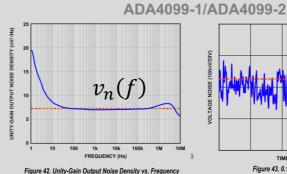
 $v_n(f) = \sqrt{\overline{S_x(f)}R} = \sqrt{\frac{\bar{x}^2}{RB}}$ This is only in white noise, $v_n(f)$ is the voltage spectrum density, with the unit of V/\sqrt{Hz}

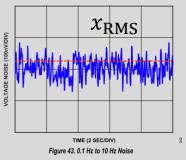


- Noise
 - Conversion
 - $0dBm = 0.632V_{PP} = 0.233 V_{RMS}$
 - Quantify and Comparison



$$v_n(f) = \sqrt{\overline{S_x(f)}R} = \sqrt{\frac{\bar{x}^2}{RB}}$$



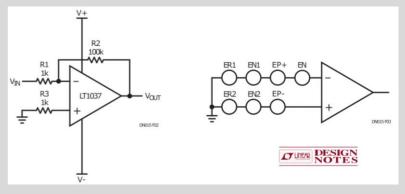


- v_n as a number gives floor
- x_{RMS} at low frequency tells flicker

	,			
NOISE PERFORMANCE				
Input Voltage Noise	f = 0.1 Hz to 10 Hz	150	150	nV p-p
	1/f noise corner	6	6	Hz
	f = 100 Hz	7	7	nV/√Hz
Over-The-Top	f = 100 Hz, V _{CM} > +V _S	8	8	nV/√Hz
Input Current Noise	f = 100 Hz	0.5	0.5	pA/√Hz
Over-The-Top	f = 100 Hz, V _{CM} > +V _S	5	5	pA/√Hz
D. 0. 1 1 1 1 0 DEDECORIUM				

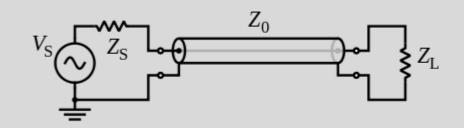


- Noise
 - Paths
 - Signal Input
 - Resistive Components
 - Semiconductor Devices
 - Non-Linear (not LTI)
 - Power Supplies
 - Indirect Coupling





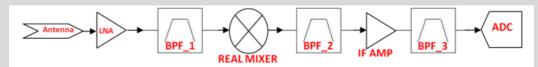
- Noise
 - Paths
 - Signal Input



• Antenna, transducer

- -> matching network
- Previous Stage of Amps

-> termination

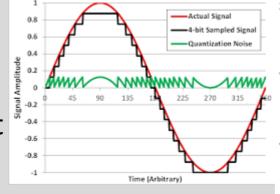


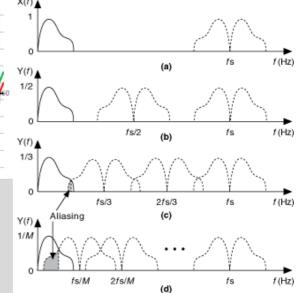
Source: Texas Instruments

$$F_n = F_1 + \frac{F_2 - 1}{G_1} + \frac{F_3 - 1}{G_1 G_2} + \cdots$$



- Noise
 - Paths
 - Signal Input
 - ADC



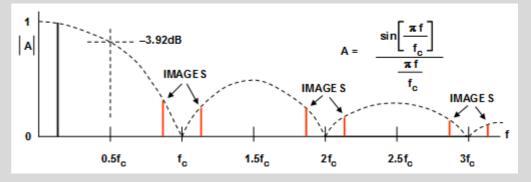


- Quantization ENOB
- Aliasing

$$x[n] = \sum_{n} \int s(t)\delta(t - nT_{S})dt$$

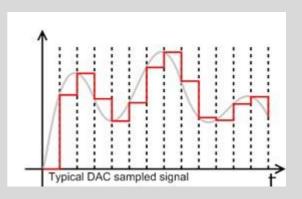


- Noise
 - Paths
 - Signal Input



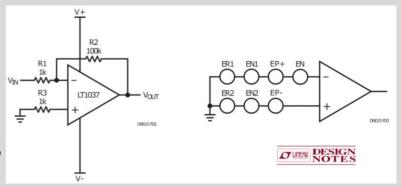
- DAC
 - Quantization ENOB
 - Mirror/Image

$$s(t) = \sum_{n} x[n] * rect\left(\frac{t}{T_{S}}\right)$$



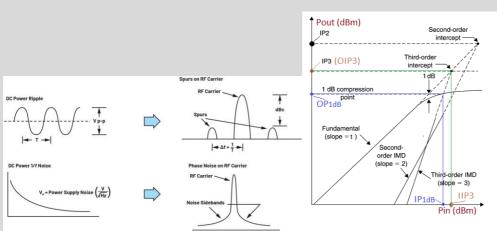


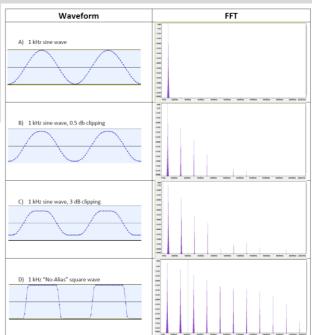
- Noise
 - Paths
 - Resistive Components
 - Semiconductor Devices





- Noise
 - Paths
 - Non-Linear (not LTI)

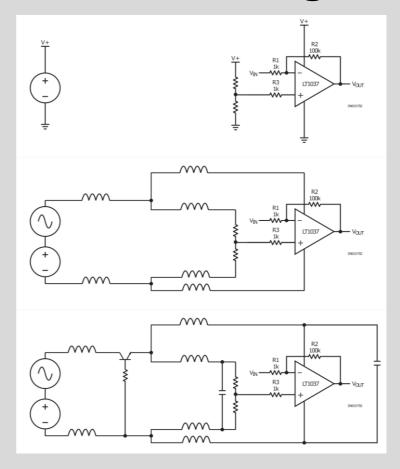






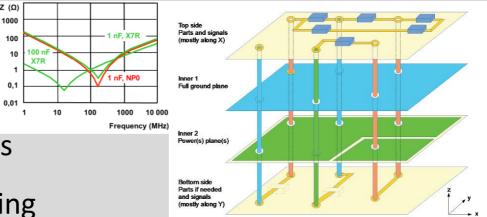
- Noise
 - Paths
 - Power Supplies
 - Indirect Coupling

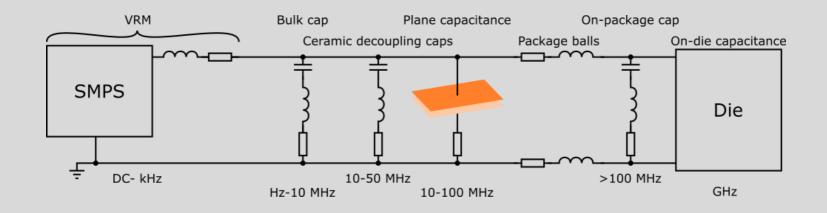
Power integrity





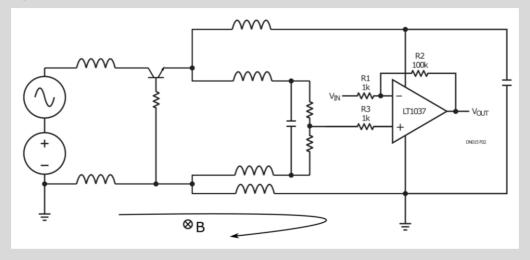
- Noise
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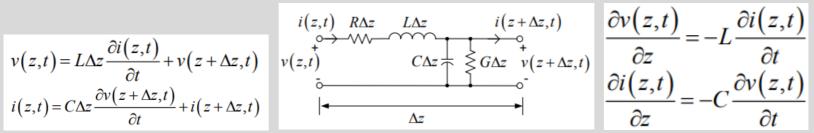
Grounding





Transmission Line Theory

$$v(z,t) = L\Delta z \frac{\partial i(z,t)}{\partial t} + v(z + \Delta z,t)$$
$$i(z,t) = C\Delta z \frac{\partial v(z + \Delta z,t)}{\partial t} + i(z + \Delta z,t)$$

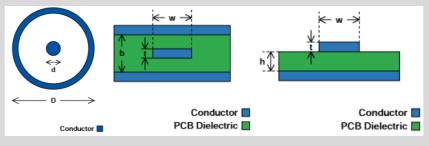


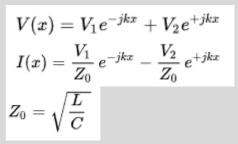
$$\frac{\partial v(z,t)}{\partial z} = -L \frac{\partial i(z,t)}{\partial t}$$
$$\frac{\partial i(z,t)}{\partial z} = -C \frac{\partial v(z,t)}{\partial t}$$

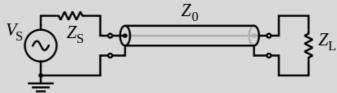
$$\frac{\partial^2 V}{\partial t^2} - u^2 \frac{\partial^2 V}{\partial x^2} = 0$$

$$\frac{\partial^2 I}{\partial t^2} - u^2 \frac{\partial^2 I}{\partial x^2} = 0$$

$$u = \frac{1}{\sqrt{LC}}$$

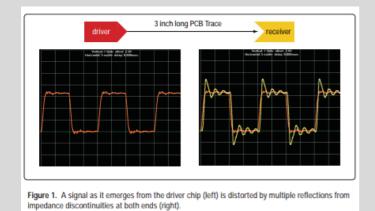




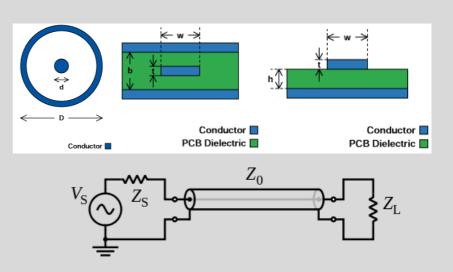




- Signal Integrity
 - Designing and Maintaining Trace Structure
 - Termination



Source: Keysight





Scattering Parameter (S-Parameter)



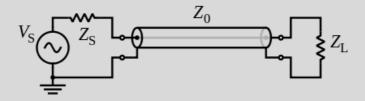
$$\begin{pmatrix}b_1\\b_2\end{pmatrix}=\begin{pmatrix}S_{11}&S_{12}\\S_{21}&S_{22}\end{pmatrix}\begin{pmatrix}a_1\\a_2\end{pmatrix}.$$

 $S_{11}\,$ is the input port voltage reflection coefficient

 $S_{12}\,$ is the reverse voltage gain

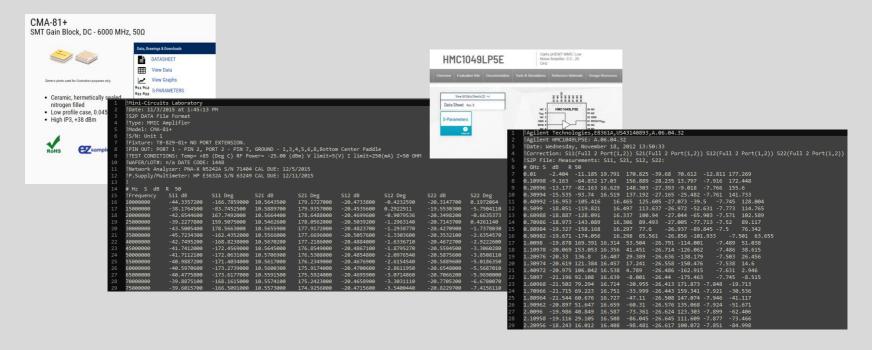
 $S_{21}\,$ is the forward voltage gain

 $S_{22}\,$ is the output port voltage reflection coefficient.



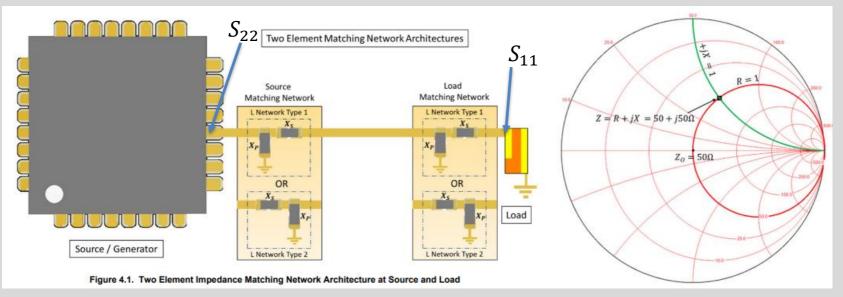


Scattering Parameter (S-Parameter)





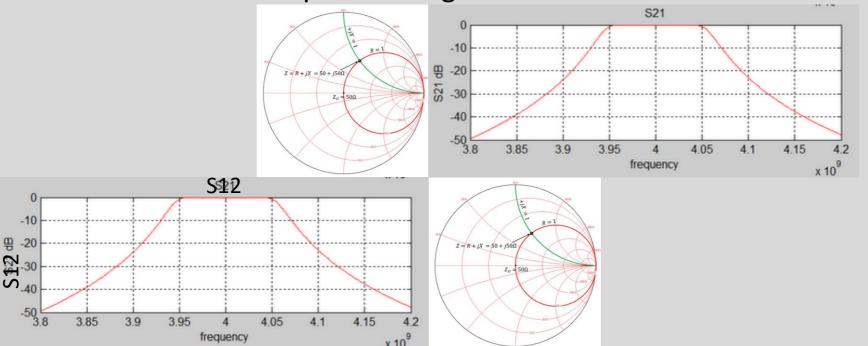
Matching Network



Source: SiLabs

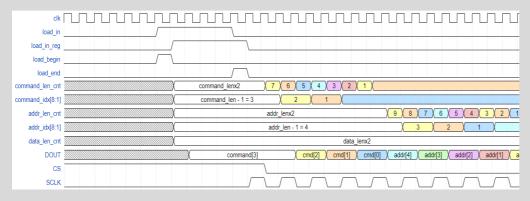


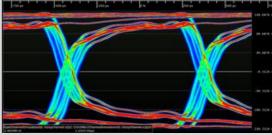
Simulation of Amplifier Design





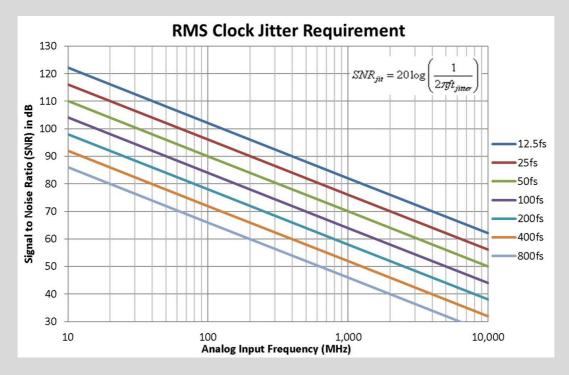
Clock Jitter/Phase noise in Digital System/Comms





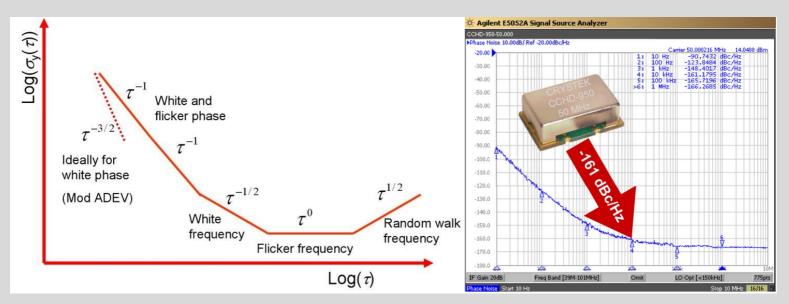


Clock Jitter/Phase noise in DAQ





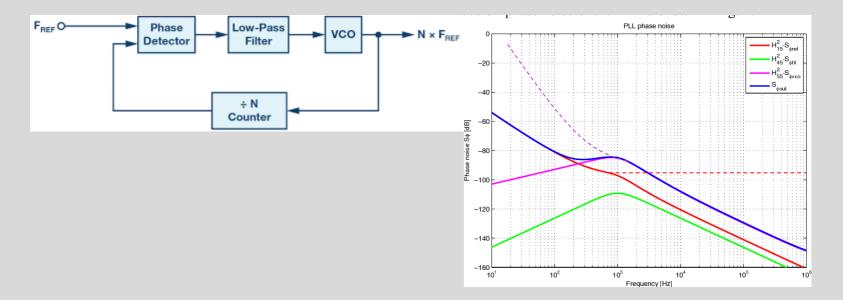
Clock Jitter/Phase noise



Source: NIST

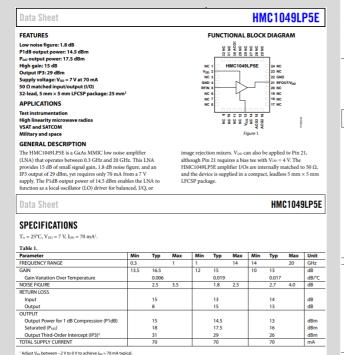


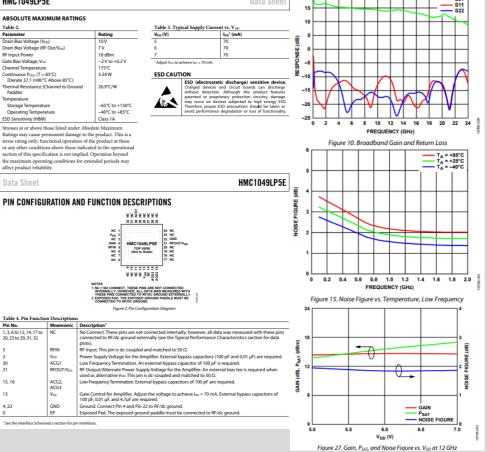
Phase Locked Loop





How to read datasheet



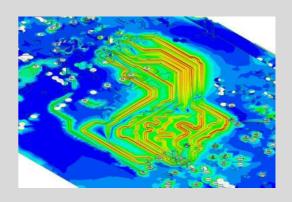




- Schematic Level
- Layout Level



- Structural model SPICE
- Behavioral model IBIS
- Scattering model S-parameter





ADS by Keysight



LTspice by Analog Devices

Qucs (under GPL license)







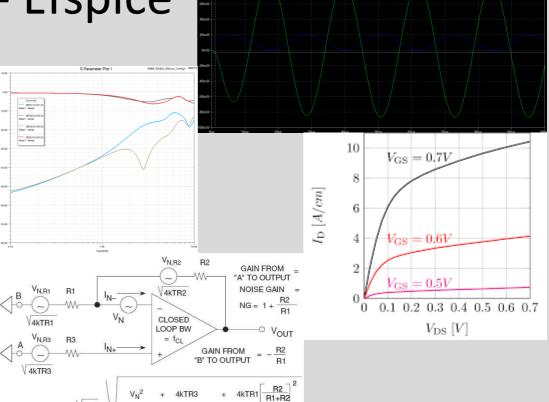




■ RTO NOISE = NG • RTI NOISE

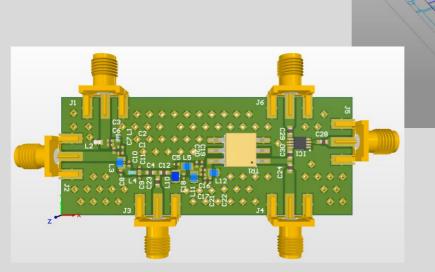
■ BW = 1.57 f_{Cl}

- Transient
- AC
- DC Sweep
- Noise



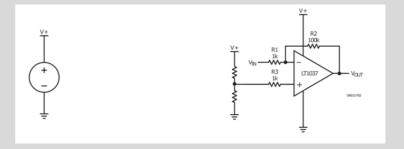


• Layout Level - Slwave





- Transient
- AC
- Noise



Simulation – Qucs – Match Circuit

